



Ref. Certif. No

NO127343

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

CB TEST CERTIFICATE

Product

SDI-12 Sensor to Cloud Gateway Device

Name and address of the applicant

Campbell Scientific Inc.
815 West 1800 North
Logan UT 84312
United States of America

Name and address of the manufacturer

Campbell Scientific Inc.
815 West 1800 North
Logan UT 84312
United States of America

Name and address of the factory

Campbell Scientific Inc.
815 West 1800 North
Logan UT 84312
United States of America

Note: When more than one factory, please report on page 2

Additional Information on Page 2

Ratings and Principal characteristics
Trademark /Brand (If any)

2.5-3.6 VDC Max output: 2A
Campbell Scientific Inc.

Customer's Testing Facility (CTF) Stage used

Model/Type Ref

Aspen10-Cell ST

Additional information (If necessary may also be reported on Page 2)

Additional Information on Page 2

A sample of the product was tested and found to be in conformity with

IEC 61010-1:2010, IEC 61010-1:2010/AMD1:2016

As shown in the Test Report Ref. No. which forms part of this Certificate

REP011952

This CB Test Certificate is issued by the National Certification Body



Philip Pedersen vei 11,
NO-1366 Lysaker, Norway

Date: 25-07-2023

Signature: Juan Z Saussey
Certification department